PCN Number:	20181210001			PCN D	ate:	12/18/2018	
Title: DLP Controller (ASIC) BUMP Site change							
Customer Conta	ct: <u>Dlp-pcn-team@list.ti.com</u> Dept: DLP CQE						
Proposed 1 st Sh	ip Date: no ear 04/01		lier than Estimated /2019 Ava		Sample 12/18/2018		
Change Type:	Change Type:						
Assembly Site			Design		🛛 Wafe	Wafer Bump Site	
Assembly Process			Data Sheet		🛛 Wafe	🛛 Wafer Bump Material	
Assembly Ma	terials		Part number change		🛛 Wafe	Wafer Bump Process	
Mechanical Specification		1 <u></u>	Test Site		Wafer Fab Site		
Packing/Shipping/Labeling		ing	Test Process		<u> </u>	Wafer Fab Materials	
					Wafe	r Fab I	Process
			PCN Det	ails			
Description of C	hange:						· · · · · ·
An alternate BUM	P/RDL site	has been	qualified for t	he devices list	ed in 'Proc	luct Af	fected' section
below.							
	Curr	ont Locati	on Now I	acation			
DUMF/RDL LOCAL	.1011 3011y	, Oita	AIIIKUI	KJ, SUUIT KU	Jied		
Amkor's standard	material a	and proces	s will be appli	ed for new Bu	mn/RDI ni	oduct	s with hump
material changing	1 from Sn/0	Cu to Sn/A	Aa.			ouuce	5 With Burnp
	,		-9-				
Material from nev	site is ex	pected to	ship no earlier	than April 1 st	, 2019. Af	er Api	ril 1 st , 2019,
customers may receive devices from either location.							
Reason for Change:							
Continuity of supply							
Anticipated imp	act on Fo	rm, Fit, F	unction, Qua	lity or Relial	oility (pos	itive	/ negative):
None							
Anticipated impact on Material Declaration							
No Impact to	o the	🖂 Mate	rial Declaratio	ns or Product	Content re	ports	are driven
Material Dec	laration	from	production da	ita and will be	available	tollowi	ng the
production release. Upon production release the revised				revised			
reports can be obtained from the <u>TI Eco-Info website</u> . There is							
	no impact to the material meeting current regulatory			lui y			
						nige.	
		I					

Changes to product identification resulting from this PCN:

Manufacturing site code on the device marking will be updated to distinguish material from two locations



MMM: Manufacturing Site

Example manufacturing site code changes:

Device	Current Marking	New Marking
DDP442x (ASE Assembly)	HAL	HCL
DDP442x (J-Devices Assembly)	HBL	HDL
DDP442x-HV	HAL	HBL

Product Affected:

Device	Orderable P/N
DDP4421	2511897-0001
DDP4422	2511898-0001
DDP4421-HV	2513282-0001
DDP4422-HV	2513283-0001
DDP5423	2512621-0001
DLPC900	DLPC900ZPC
DLPC6421	DLPC6421ZPC

Qualification Data

This qualification has been developed for the validation of this change. The qualification data validates that the proposed change meets the applicable released technical specifications. **Qual Vehicle:** DDP4421 (ASE Assembly), DDP4421(J-Devices Assembly) and DDP4421-HV

Qualification: 🗌 Plan 🛛 Test Results				
Test	Conditions	Sample Size	Results	
Precondition	30°C/70% RH/216hrs, 255°C max (4 times)	96pcs	Pass	
ТСТ	-55°C/125°C; 1000cycles	32pcs	Pass	
uHAST	110°C/85% RH; 500hrs	32pcs	Pass	
THB	85°C/85% RH, Vdd max; 1000hrs	32pcs	Pass	
HTS	150°C; 1000hrs	32pcs	Pass	

For questions regarding this notice, e-mails can be sent to the regional contacts shown below or your local Field Sales Representative.

Location	E-Mail
DLP [®] Products	<u>Dlp-pcn-team@list.ti.com</u>
USA	PCNAmericasContact@list.ti.com
Europe	PCNEuropeContact@list.ti.com
Asia Pacific	PCNAsiaContact@list.ti.com
Japan	PCNJapanContact@list.ti.com